High Resolution Spectral Domain OCT

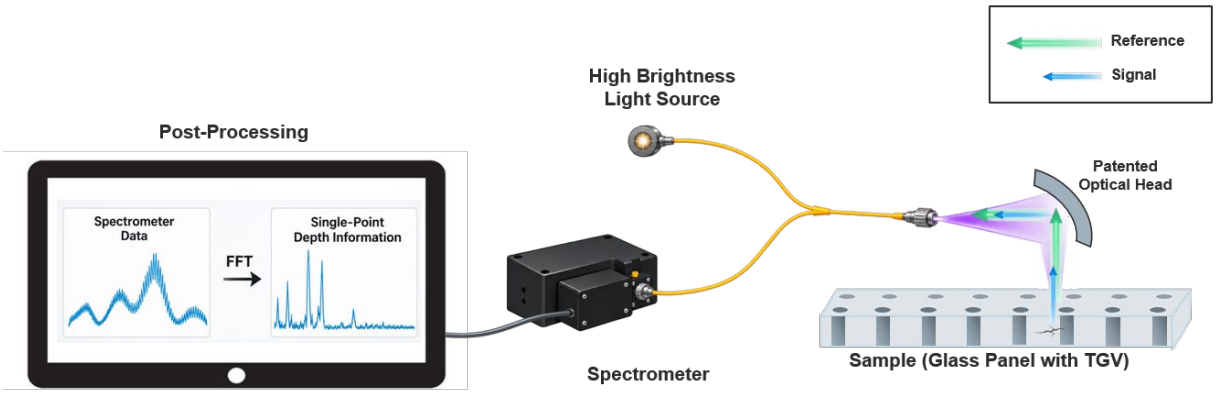
Non-Destructive Testing for Subsurface Defects

Identification and measurement of subsurface defects in glass substrates, wide band gap materials, and optical elements.

HR SD-OCT Demonstration System

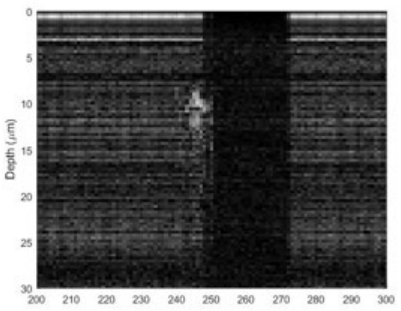
High-Brightness Light Source + **Patented Optical Head** + **High-Speed Spectrometer** + **Imaging Software**

HR SD-OCT: Principle of Operation



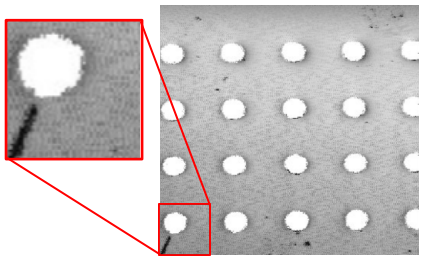
Patented high-resolution optical design enables non-destructive detection and characterization of subsurface defects, with a compact optical head designed for integration into inspection systems.

Depth-Resolved Defect Detection



Sequential A scans

Subsurface Inspection of Glass Substrates



With Copper Filled Vias

The SD-OCT system described here is in development. For more information, please reach out to info@energetiq.com.

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